## Supplemental Information for: Microgel Film Dynamics Modulate Cell Adhesion Behavior

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Figure S1. Reaction scheme for EDC/NHS film cross-linking treatment of PEI films.



**Figure S2**. Brightfield microscopy images for self-healing assessment of BIS/pDADMAC 4 layer films after exposure to cell culture medium. (a-c) untreated (d-f) crosslink-treated. (a,d) before damage (b,e) after 30% linear strain applied (c,f) healed with water after damage.



**Figure S3**. Brightfield microscopy images for self-healing assessment of BIS/PEI 4 layer films after exposure to cell culture medium. (a-c) untreated (d-f) crosslink-treated. (a,d) before damage (b,e) after 60% linear strain applied (c,f) healed with water after damage.



**Figure S4**. Intra- and inter-sample variability for AFM force maps for each type of film. Each column represents one force map with error bars representing the standard deviation of moduli within the map.

**Table S1**. Dynamic light scattering results for microgels used in this study. All data were collected at 25 °C in either PBS (pH 7.4) or Formate buffer (pH 3.0).

Microgel	R <sub>H</sub> , nm (pH 3.0)	R <sub>H</sub> , nm (pH 7.4)
pNIPAm, BIS, Aac	239 ± 77	524 ± 104
pNIPAm, PEGDA, Aac	277 ± 25	$510 \pm 31$



Figure S5. Film thickness as determined via atomic force microscopy in air.